#### HAMAMATSU



# **CCD** area image sensor

S10810

# Front-illuminated FFT-CCDs for X-ray imaging

The S10810 is an FFT-CCD image sensor suitable for intra-oral X-ray imaging in dental diagnosis. The S10810 has 1.5 mega (1500  $\times$  1000) pixels, each of which is 20  $\times$  20  $\mu$ m in size. The FOP (fiber optic plate) used as an input window is as thin as 1.5 mm, making high resolution as well as highly resistant to X-ray irradiation. The scintillator coated on the FOP is optimized to have high X-ray sensitivity and high resolution (20 Lp/mm).

The S10810 is an easy-to-use X-ray imaging module, with added functions such as a cable assembly and X-ray trigger circuit. The S10810 is pin-compatible with the S8981-02C and also S10811 ( $1700 \times 1200$  pixels).

#### Features

- X-ray monitoring photodiode incorporated
- Compact size
- High dynamic range: 12-bit
- Long-term stability For use under 100000 shots (60 kVp, 30 mR X-ray irradiation)
- Resolution: 20 Lp/mm
- **1500 (H)** × **1000 (V)** pixel format
- Pixel size: 20 × 20 μm
- Coupled with FOS for X-ray imaging
- 100 % fill factor
- Low dark signal
- Low readout noise
- MPP operation
- AC/DC X-ray source adapted

## Applications

- **■** Intra-oral X-ray imaging in dental diagnosis
- General X-ray imaging
- Non-destructive inspection

### General ratings

Parameter	Specification	
CCD structure	Full frame transfer	
Fill factor	100 %	
Cooling	Non-cooled	
Number of pixels	1508 (H) × 1002 (V)	
Number of active pixels	1500 (H) × 1000 (V)	
Pixel size	20 (H) × 20 (V) μm	
Active area	30 (H) × 20 (V) mm	
Vertical clock phase	2 phases	
Horizontal clock phase	2 phases	
Output circuit	Emitter follower without load resistance	
Dimensions	41.0 (H) × 26.4 (V) mm	
Reliability	100000 shots at 60 kVp, 30 mR	
Window	Scintillator on 1.5 mm FOP	

# **□** Absolute maximum ratings (Ta=25 °C)

Parameter	Symbol	Min.	Тур.	Max.	Unit
Storage temperature	Tstg	-20	-	+70	°C
Operating temperature	Topr	0	-	+40	°C
OD voltage	Vod	-0.5	-	+20	V
RD voltage	Vrd	-0.5	-	+18	V
SG voltage	Vsg	-15	-	+15	V
OG voltage	Vog	-15	-	+15	V
RG voltage	VRG	-15	-	+15	V
TG voltage	VTG	-15	-	+15	V
Vertical clock voltage	VP1V, VP2V	-15	-	+15	V
Horizontal clock voltage	VP1H, VP2H	-15	-	+15	V
Vcc voltage	Vcc	0	-	+7	V

# **□** Operating conditions (MPP mode, Ta=25 °C)

Parameter		Symbol	Min.	Тур.	Max.	Unit
Output transistor drain voltage		Vod	12	15	-	V
Reset drain voltage		Vrd	12	13	14	V
Output gate voltage		Vog	-0.5	2	5	V
Substrate voltage		Vss	-	0	-	V
Vertical shift register	High	VP1VH, VP2VH	0	3	6	V
clock voltage	Low	VP1VL, VP2VL	-9	-8	-7	V
Horizontal shift register	High	VP1HH, VP2HH	0	3	6	V
clock voltage	Low	VP1HL, VP2HL	-9	-8	-7	V
Cumming gate voltage	High	VsgH	0	3	6	V
Summing gate voltage	Low	VsGL	-9	-8	-7	V
Donot goto voltago	High	VRGH	0	3	6	V
Reset gate voltage	Low	VRGL	-9	-8	-7	V
Transfer gate valtage	High	VTGH	0	3	6	V
Transfer gate voltage Low		VTGL	-9	-8	-7	V
+5 V power supply voltage		Vcc	4.75	5	5.25	V

## **➡** Electrical characteristics (Ta=25 °C)

Parameter	Symbol	Min.	Тур.	Max.	Unit
Signal output frequency	fc	-	1	-	MHz
Vertical shift register capacitance	CP1V, CP2V	-	60000	-	pF
Horizontal shift register capacitance	СР1Н, СР2Н	-	550	-	pF
Summing gate capacitance	CsG	-	220	-	pF
Reset gate capacitance	CRG	-	220	-	pF
Transfer gate capacitance	Стс	-	450	-	pF
Charge transfer efficiency *1	CTE	0.99995	0.99998	-	-
DC output level *2	Vout	5	8	11	V
Output impedance *2	Zo	-	500	-	Ω
Power dissipation *2 *3	Р	-	75	-	mW
+5 V power supply current	Icc	-	2	-	mA

<sup>\*1:</sup> Measured at half of the full well capacity. CTE is defined per pixel.

<sup>\*2:</sup> VoD=15 V

<sup>\*3:</sup> Power dissipation of the on-chip amplifier

### **■** Electrical and optical characteristics (Ta=25 °C, VoD=15 V, unless otherwise noted)

Parameter		Symbol	Min.	Тур.	Max.	Unit	
Vertical		Vertical		100	200	-	
Full well capa	city	Horizontal	Fw	-	300	-	ke <sup>-</sup>
		Summing		-	600	-	
CCD node ser	nsitivity *4		Sv	1.0	1.4	-	μV/e⁻
Dark current	(MPP mode) *5		DS	-	250	2500	e <sup>-</sup> /pixel/s
Readout noise	Readout noise *6		Nr	-	60	-	e⁻ rms
Dynamic rang	Dynamic range *7		DR	-	3333	-	-
X-ray respons	se non-uniformi	ty *8 *9	XRNU	-	±10	±30	%
	Point	White spots		-	-	20	
Blemish *10	defects *11	Black spots	_	-	-	20	
Cluster defects *12		_	-	-	3	-	
	Column defects *13			-	-	1	
X-ray resolution *8		ΔR	15	20	-	Lp/mm	

<sup>\*4:</sup> VoD=15 V, RL (load resistance of emitter follower)=1  $k\Omega$ 

Noise: Fixed pattern noise (peak to peak)

In the range that excludes 5 pixels from edges to the center at every position

<sup>\*5:</sup> Dark signal doubles for every 5 to 7 °C.

<sup>\*6: -40 °</sup>C, operating frequency is 1 MHz.

<sup>\*7:</sup> Dynamic range = Full well capacity / Readout noise \*8: X-ray irradiation of 60 kVp, measured at half of the full well capacity

<sup>\*9:</sup> XRNU (%) = Noise / Signal × 100

<sup>\*10:</sup> Refer to "Characteristics and use of FFT-CCD area image sensor" of technical information.

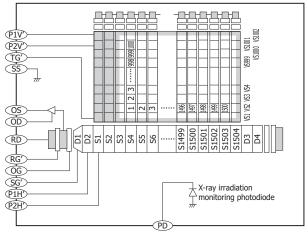
<sup>\*11:</sup> White spots > 10 times of Max. Dark signal (2500 e<sup>-</sup>/pixel/s)

Black spots > 50 % reduction in response relative to adjacent pixels, measured at half of the full well capacity

<sup>\*12:</sup> Continuous 2 to 9 point defects

<sup>\*13:</sup> Continuous > 10 point defects

#### **Device structure**



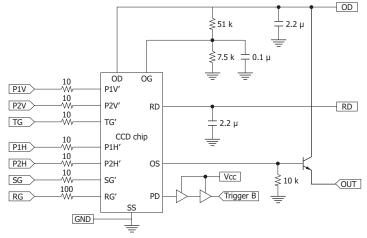
KMPDC0163EA

#### Pixel format

	Left ← Horizontal direction → Right						
Blank	Optical black	Isolation	Effective	Isolation	Optical black	Blank	
2	2	1	1500	1	0	2	

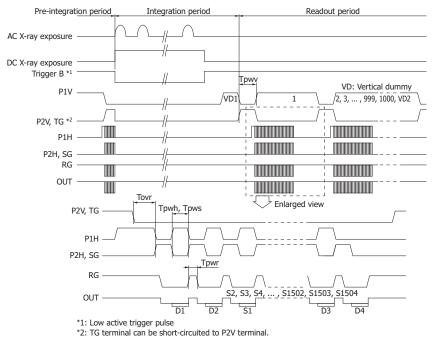
Top ← Vertical direction → Bottom				
Isolation Effective Isolation				
1	1000	1		

### - On-board circuit



KMPDC0314EA

## - Timing chart



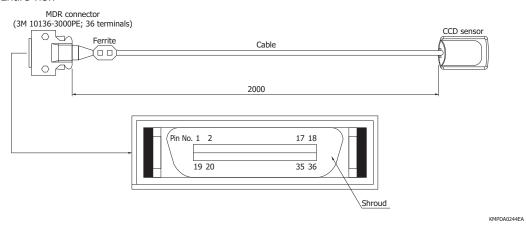
Min. Unit Parameter Symbol Тур. Max. Pulse width \*14 tpwv 30 60 μs P1V, P2V, TG Rise and fall times tprv, tpfv 200 ns Pulse width 100 500 tpwh ns Rise and fall times \*14 P1H, P2H tprh, tpfh 5 ns Duty ratio 50 -% Pulse width 100 500 tpws ns SG Rise and fall times 3 tprs, tpfs ns 50 Duty ratio % Pulse width tpwr 10 50 ns RG Rise and fall times 3 tprr, tpfr ns TG-P1H Overlap time 18 36 tovr μs

KMPDC0315FA

<sup>\*14:</sup> The clock pulses should be overlapped at 50 % of maximum amplitude.

# - Dimensional outlines (unit: mm)

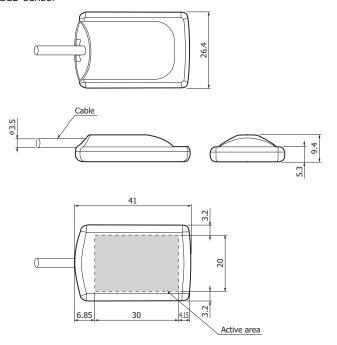
#### ■ Entire view



\* The shield of cable and the shroud of MDR connector are short-circuited.

Take due care of EMC and ESD when connected to 0 V reference and the ground.

#### ■CCD sensor



#### Pin connections

Pin No.	Symbol	Description	Remark
1	GND	Ground	
2	Vcc	+5 V power supply	
3	SG	Summing gate	Same timing as P2H
4	Trigger B	Trigger B output	
5	RG	Reset gate	
6	NC		
7	Reserve		Should be opened
8	NC		
9	RD	Reset drain	
10	NC		
11	OD	Output transistor drain	
12	NC		
13	OUT	Sensor output	
14	NC		
15	GND	Ground	
16	NC		
17	P1V	CCD vertical register clock-1	
18	Reserve		Should be opened
19	Reserve		Should be opened
20	P2H	CCD horizontal register clock-2	
21	NC		
22	P1H	CCD horizontal register clock-1	
23	NC		
24	GND	Ground	
25	NC		
26	RD	Reset drain	
27	NC		
28	OD	Output transistor drain	
29	NC		
30	GND	Ground	
31	NC		
32	OUT	Sensor output	
33	NC		
34	P2V	CCD vertical register clock-2	
35	NC		
36	TG	Transfer gate	Same timing as P2V

#### Precautions for use (electrostatic countermeasures)

- · Handle these sensors with bare hands or wearing cotton gloves. In addition, wear anti-static clothing or use a wrist band with an earth ring, in order to prevent electrostatic damage due to electrical charges from friction.
- · Avoid directly placing these sensors on a work-desk or work-bench that may carry an electrostatic charge.
- · Provide ground lines or ground connection with the work-floor, work-desk and work-bench to allow static electricity to discharge.
- · Ground the tools used to handle these sensors, such as tweezers and soldering irons.

It is not always necessary to provide all the electrostatic measures stated above. Implement these measures according to the amount of damage that occurs.

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